

14	104293 324/\$.ccls.	USPAT; 2003/02/26 US-PGPUB; 16:29 EPO; JPO; DERWENT; IBM_TDB USFAT; 2003/02/26 US-PGPUB; 16:30 EPO; JPO; DERWENT; IBM_TDB USFAT; 2003/02/26 US-PGPUB; 16:43 EPO; JPO; DERWENT; IBM_TDB USFAT; 2003/02/26 US-PGPUB; 16:43 EPO; JPO; DERWENT; IBM_TDB
15	36591 714/\$.ccls.	
16	125 ((testing and semiconductor and integrated and circuit) and (analog and digital and convert\$4) and (test and board and memory)) and 324/\$.ccls.	
17	141 ((testing and semiconductor and integrated and circuit) and (analog and digital and convert\$4) and (test and board and memory)) and 714/\$.ccls.	